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OTH	ER D	OCUMENTS (Including Author, Title, Date, Partition) Pag	res Fire V	
DN		VLSI Technology, Edited by S.M. Sze., McGraw-Hill Book Company, AChapter 6 Dielectric and Patrollica Deposition A.C. Adams, pp. 233-235+		
+	\downarrow	J. appl. Phys., Vol. 29, No. 11, Nov. 1990, pp.	ine Sillcon Obtained From Pyrolysis	of Si-HL and Appending
+	Bulletin, Vol. 26, No. 3A, Aug. 1983, pp. 921-922* Madsen et al., Ala Sim Doping of Silicon Films Prepared by Low Pressure Chemical Vapor Deposition In Disilane and Phosphine®, J. Electrochem. Soc. Col. 127			BM Technical Disclosure
1				Vapor Denoviries III
 	Wolf et al., ASilicon Processing for the VLSI Era@, Vol. 1: Process Technology, Lattice Press, S. (1986), pp. 175-176* H. Ohshima et al., AFunure Trends for TFT Integrated Circuits on Glass Substrates@, IEDM (IEE 160* Journal of Non-Crystalline Solids, Vols. 59, 60, Dec. 1983, Part II, pp. 731-734, Proceedings of the al.* Solar Calle 2, (1989)		Stice Proce Summer David	
_			egrated Circuits on Glass Substrates@, IEDM (IEEE 1989), pp. 15	
		Solar Cells 2, (1980). Alavestigation of the Hydrogen and Impurity Contents of Amorphous Silicon by Secondary Hydrogen and David E. Carlson, RCA Laboratories, Princeton, NJ pp. 365-376*		
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		Amiliating Amorphous Silicon Transistors and Intern	med Cincil	104
N	शर्यद	A(lavited) Amorphous Silicon Transistors and Integrated Circuits@, Masakiyo Massumura, Japanese Journal of Applied Physics, Vol. 22 (1983), Supplement 22-1, pp. 487-491. Lewis, et al., "ACTIVE MATRIX LIQUID CRYSTAL DISPLAY DESIGN USING LOW AND HIGH TEMPERATURE PROCESSED POLYSILICON TFIS," CH2865-4/90/0000-0843, IEDM90, pp. 843-846.		
<u> </u>	-		, C122603-4/90/0000-0843, IED	M90, pp. 843-846.
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